

PSE Technology Corporation

SPECIFICATION FOR APPROVAL

CUSTOMER	
NOMINAL FREQUENCY	32.768 KHz
PRODUCT TYPE	TYPE G8 SMD CRYSTAL
SPEC. NO. (P/N)	G83270022
CUSTOMER P/N	
ISSUE DATE	Jun.16,2016
VERSION	Α

APPROVED	PREPARED	QA
Brenda	Clane	Dong Jang
APPROVED BY	CUSTOMER:	AVL Status
Please return one copy	with approval to PSE-TW	

PSE Technology Corporation

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*RoHS Compliant

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E0-R-4-014 Rev. E Page i

G83270022

VER. A 16-Jun-16

VERSION HISTORY

Version No.	Version Date	Customer Receipt Date	Supplier Receipt Date	Description	Notes
Α	Jun.16,2016			Initial Release	
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E0-R-4-014 Rev. E

G83270022

VER. A 16-Jun-16

ELECTRICAL SPECIFICATIONS

SRe Part Number: G83270022

Parameters	Symbol	Specifications	Units	Notes
Nominal Frequency	Fn	32.768	KHz	
Frequency Tolerance	FT	± 10	ppm	at 25°C ± 5°C
Load Capacitance	CL	12.5	pF	Тур.
Drive Level	DL	0.1 / 0.5	μW	Typ. / Max.
Equivalent Series Resistance	ESR	70	ΚΩ	Max.
Temperature Coefficient	K	-0.03	ppm/°C ²	± 0.01ppm/°C ²
Operating Temperature Range	TR	-40 to 85	°C	
Shunt Capacitance	C0	1.5	pF	Тур.
Motional Capacitance	C1	6.5	fF	Тур.
Quality Factor	Q	13	K	Min.
Aging		± 3	ppm	Max. 1st year
Storage Temperature Range		-40 to 85	°C	
Insulation Resistance		500	МΩ	Min.

Reliability (Mechanical and environmental performances)

No.	Test Items	Conditions	Requirements
1	Bending test	Apply pressure in the direction of the arrow at a rate of about 0.5mm/s until bent width reaches 5mm, and hold for 30 seconds.	Without mechanical damage such as breaks and satisfy sealing specification. Frequency change: Within ±5ppm
2	Shear test	Apply 20N(2.04kgf) static load to the core of quartz crystal units in the direction of the arrow using a R0.5 scratch tool, then hold for 5 seconds.	• Equivalent series resistance(E.S.R) change: Within 5kΩ
3	Core body strength	Apply 10N(1.02kgf) static load to the quartz crystal units center in the direction of the arrow using a R0.5 pushing tool, then hold for 10 seconds.	
4	Vibration	Frequency sweep method shall be applied as follows. Quartz crystal units shall be vibrated with the sweeping frequency from 10Hz to 55Hz and return to 10Hz in 1 minute, with 1.5mm amplitude. This vibration shall be applied for 2 hours in each 3 perpendicular axes. Other procedures conform to JIS C 60068-2-6.	
5	Shock	Quartz crystal units shall be accelerated at 9810m/s2 by 1ms pulse duration. This shock shall be applied 3 times in each 3 perpendicular axes. Other procedures conform to JIS C 60068-2-27.	

G83270022

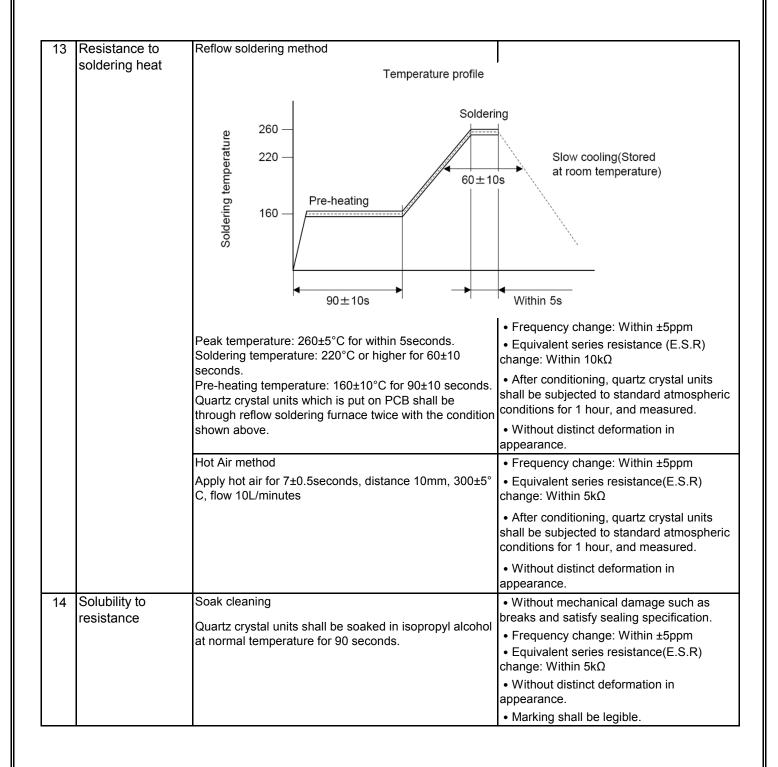
VER. A 16-Jun-16

6	Cold	atmosphere for 1000 hours. Other procedures conform • Equiv	lency change: Within ±5ppm ralent series resistance(E.S.R) · Within 5kΩ
7	Dry heat	atmosphere for 100 hours. Other procedures conform to shall be	conditioning, quartz crystal units subjected to standard atmospheric ns for 1 hour, and measured.
8	Damp heat	Quartz crystal units shall be stored in the 40±2°C atmosphere with 90 to 95% relative humidity for 1000 hours. Other procedures conform to JIS C 60068-2-3.	
9	Change of temperature	Quartz crystal units shall be subjected successively 100 cycles of temperature change shown below. Other procedures conform to JIS C 0025.	
		Temperature Duration	
		1 -40±3 °C 30min.	
		2 Normal temperature Within 30 sec.	
		3 100±2°C 30min.	
		4 Normal temperature Within 30 sec.	
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10	Sealing	Both the test methods specified below shall be applied.	Constitution to the Constitution of the Consti
		•	out repetitive leaking bubbles from crystal units.
			-9 Pa⋅m3/s or less
		spectrometric leakage detector to measure the leakage rate of helium gas.	0 1 0 1110/0 01 1000
	1		
11	Aging	Quartz crystal units shall be stored in the 85±3℃ • Frequ	uency change: Within ±5ppm
11	Aging	atmosphere for 720±12 hours. • Equiv	ency change: Within ±5ppm alent series resistance(E.S.R) Within 5kΩ
11	Aging	atmosphere for 720±12 hours. • Equiv change: • After shall be	alent series resistance(E.S.R) Within 5kΩ conditioning, quartz crystal units
11	Aging Solder-ability	atmosphere for 720±12 hours. • Equivorange: • After a shall be condition Terminals coated with flux shall be immersed in the	ralent series resistance(E.S.R) Within 5kΩ conditioning, quartz crystal units subjected to standard atmospheric
		atmosphere for 720±12 hours. • Equivorange: • After a shall be condition Terminals coated with flux shall be immersed in the	alent series resistance(E.S.R) Within 5kΩ conditioning, quartz crystal units subjected to standard atmospheric ns for 1 hour, and measured. num 95% of immersed terminal sha
		atmosphere for 720±12 hours. • Equivorange: • After of shall be condition Terminals coated with flux shall be immersed in the solder bath for 3.5±0.5 seconds. • Equivorange: • After of shall be condition • Minimum be coveraged.	alent series resistance(E.S.R) Within 5kΩ conditioning, quartz crystal units subjected to standard atmospheric ns for 1 hour, and measured. hum 95% of immersed terminal sha
		atmosphere for 720±12 hours. • Equivorange: • After a shall be condition Terminals coated with flux shall be immersed in the solder bath for 3.5±0.5 seconds. • Equivorange: • After a shall be condition	alent series resistance(E.S.R) Within 5kΩ conditioning, quartz crystal units subjected to standard atmospheric ns for 1 hour, and measured. num 95% of immersed terminal sha

E0-R-4-014 Rev. E Page 2

G83270022

VER. A 16-Jun-16

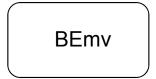


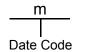
G83270022

VER. A

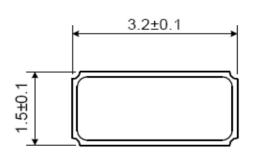
16-Jun-16

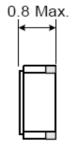
Marking

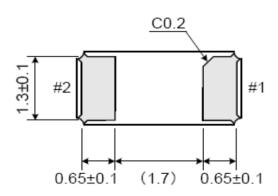




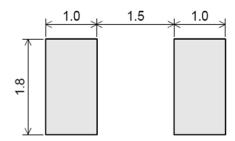
Dimensions (Units: mm)



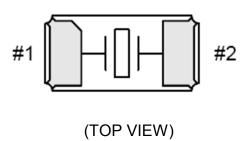




Recommended Soldering Pattern



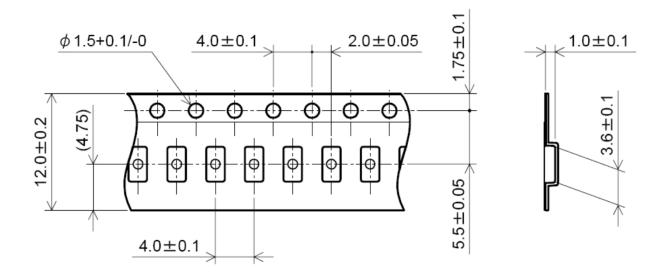
Internal connection



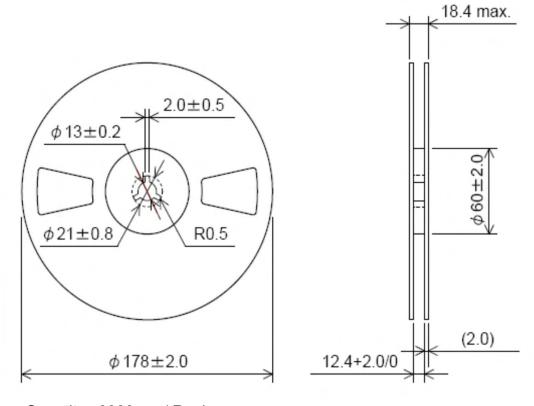
G83270022

VER. A 16-Jun-16

TAPING (Units: mm)



REEL (Units: mm)



Quantity: 3000pcs / Reel

E0-R-4-014 Rev. E Page 5